Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/618,850	TANAKA ET AL.
Examiner	Art Unit
David Nhu	2818

SEARCHED			
Class	Subclass	Date	Examiner
438	30	7/6/2005	DN
i	45, 46	1	i
	77		
	154, 157		
	159		
	163, 164		
	191, 194		
	197		
	181		
	217		
	174		
	706	_\/ ·	
V		. V	Ψ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	30	11/13/2006	DN
V	197	✓	V
	181		/
	_		

SEARCH I (INCLUDING SEAR)
	DATE	EXMR
SEARCHED IN EAST	7/6/2005	DN
SEARCHED IN EAST	6/12/2006	DN
SEARCHED IN EAST	11/13/2006	DN
		•